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"[Embedded - Microcontrollers](#)" refer to small, integrated circuits designed to perform specific tasks within larger systems. These microcontrollers are essentially compact computers on a single chip, containing a processor core, memory, and programmable input/output peripherals. They are called "embedded" because they are embedded within electronic devices to control various functions, rather than serving as standalone computers. Microcontrollers are crucial in modern electronics, providing the intelligence and control needed for a wide range of applications.

Applications of "[Embedded - Microcontrollers](#)"

Details

Product Status	Active
Core Processor	ARM® Cortex®-M0+
Core Size	32-Bit Single-Core
Speed	32MHz
Connectivity	CANbus, I ² C, SCI, SPI, UART/USART, USB
Peripherals	LVD, POR, PWM, WDT
Number of I/O	35
Program Memory Size	64KB (64K x 8)
Program Memory Type	FLASH
EEPROM Size	4K x 8
RAM Size	16K x 8
Voltage - Supply (Vcc/Vdd)	1.6V ~ 5.5V
Data Converters	A/D 14x14b; D/A 1x12b
Oscillator Type	Internal
Operating Temperature	-40°C ~ 105°C (TA)
Mounting Type	Surface Mount
Package / Case	48-LQFP
Supplier Device Package	48-LFQFP (7x7)
Purchase URL	https://www.e-xfl.com/product-detail/renesas-electronics-america/r7fs124763a01cfl-aa1

1.4 Function Comparison

Table 1.13 Function comparison

Parts number	R7FS124773A01CFM/ R7FS124763A01CFM/ R7FS124773A01CNB/	R7FS124773A01CFL/ R7FS124763A01CFL/ R7FS124773A01CNE	R7FS124773A01CNF	R7FS124772A01CLM/ R7FS124762A01CLM	
Pin count	64	48	40	36	
Package	LQFP/QFN	LQFP/QFN	QFN	LGA	
Code flash memory	128/64 KB				
Data flash memory	4 KB				
SRAM	16 KB				
	Parity	4 KB			
System	CPU clock	32 MHz			
	ICU	Yes			
	KINT	8	5	5	4
Event link	ELC	Yes			
DMA	DTC	Yes			
Timers	GPT32	1			
	GPT16	6	6	4	4
	AGT	2	2	2	2
	RTC	Yes			
	WDT/IWDT	Yes			
Communication	SCI	3			
	IIC	2			
	SPI	2			
	CAN	Yes			
	USBFS	Yes			
Analog	ADC14	18	14	12	11
	DAC12	1			
	ACMPLP	2			
	TSN	Yes			
HMI	CTSU	31	23	17	13
	KINT	8	5	5	4
Data processing	CRC	Yes			
	DOC	Yes			
Security	AES and TRNG				

1.6 Pin Assignments

Figure 1.3 to Figure 1.8 show the pin assignments.

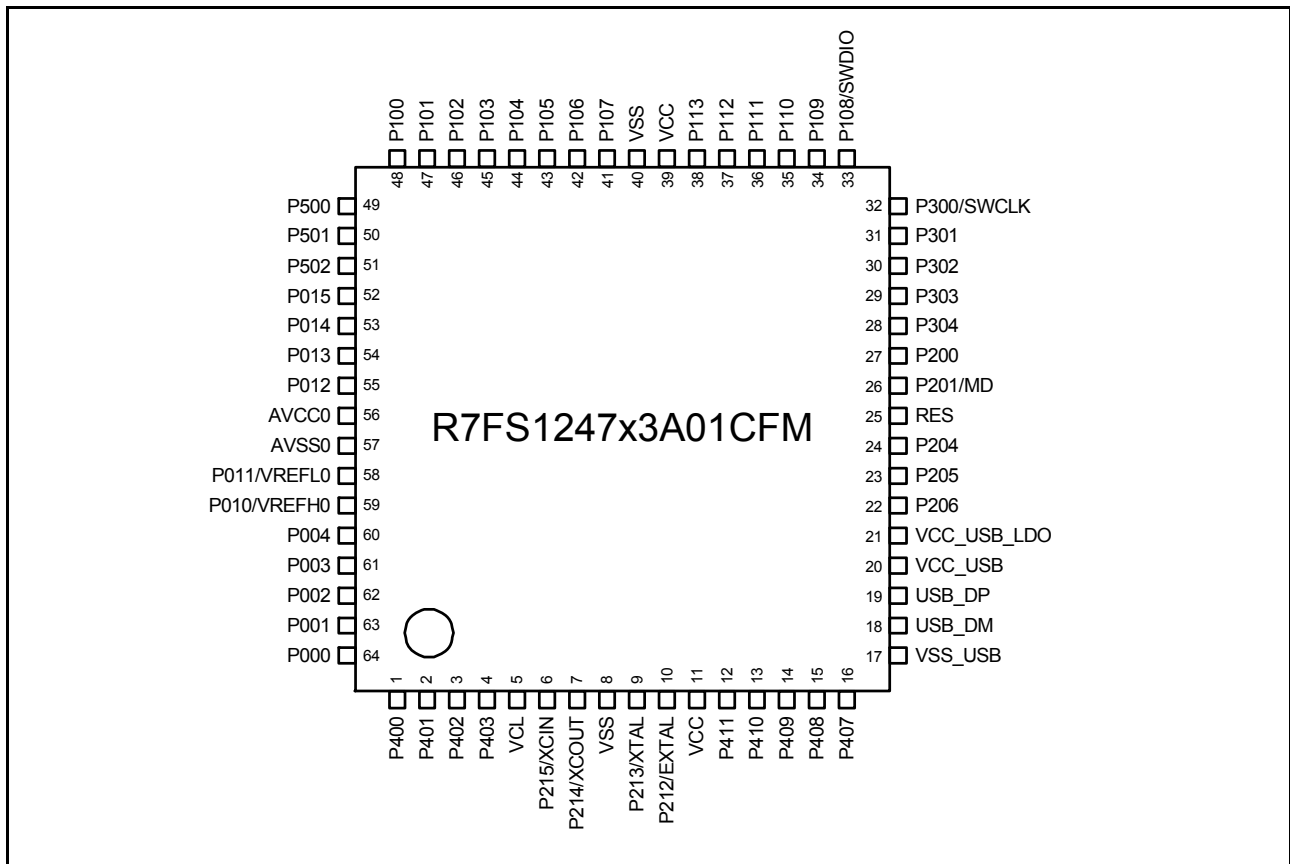


Figure 1.3 Pin assignment for LQFP 64-pin (top view)

2. Electrical Characteristics

Unless otherwise specified, the electrical characteristics of the MCU are defined under the following conditions:

$VCC^{*1} = AVCC0 = VCC_USB^{*2} = VCC_USB_LDO^{*2} = 1.6$ to $5.5V$, $VREFH0 = 1.6$ to $AVCC0$,

$VSS = AVSS0 = VREFL0 = VSS_USB = 0V$, $T_a = T_{opr}$

Note 1. The typical condition is set to $VCC = 3.3V$.

Note 2. When USBFS is not used.

Figure 2.1 shows the timing conditions.

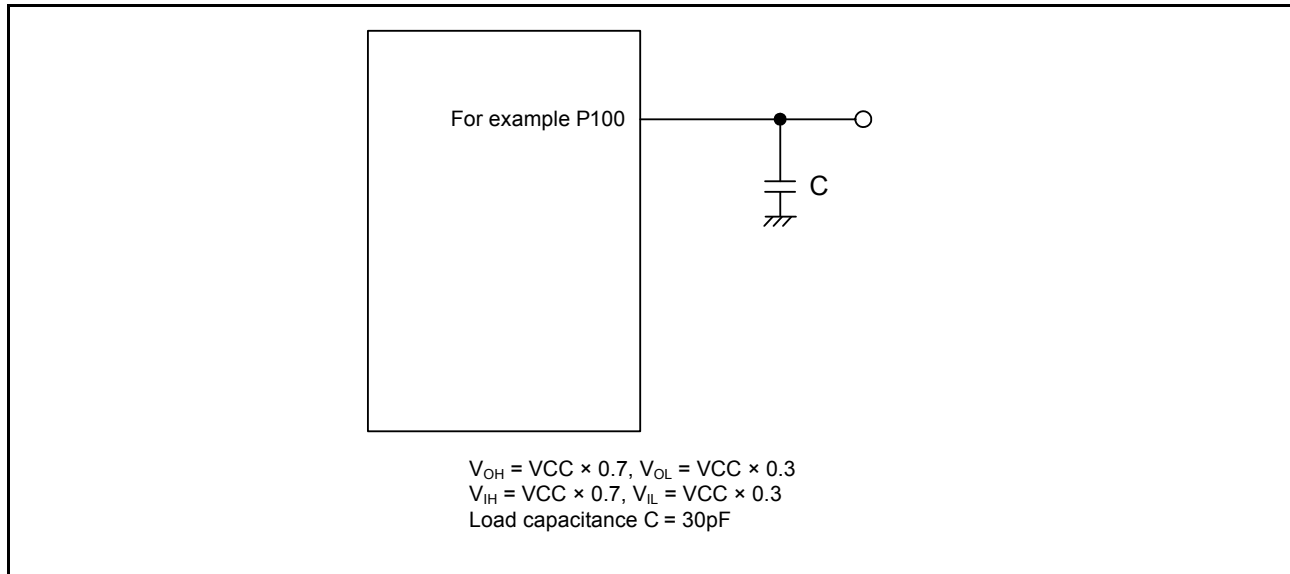


Figure 2.1 Input or output timing measurement conditions

The measurement conditions of timing specification in each peripherals are recommended for the best peripheral operation. However, make sure to adjust driving abilities of each pins to meet your conditions.

Each function pin used for the same function must select the same drive ability. If I/O drive ability of each function is mixed, the AC specification of the function is not guaranteed.

Table 2.5 I/O V_{IH} , V_{IL} (2)Conditions: $V_{CC} = AV_{CC0} = 1.6$ to 2.7 V

Parameter		Symbol	Min	Typ	Max	Unit	Test Conditions
Schmitt trigger input voltage	RES, NMI Peripheral input pins	V_{IH}	$V_{CC} \times 0.8$	-	-	V	-
		V_{IL}	-	-	$V_{CC} \times 0.2$		
		ΔV_T	$V_{CC} \times 0.01$	-	-		
Input voltage (except for Schmitt trigger input pin)	5V-tolerant ports*1	V_{IH}	$V_{CC} \times 0.8$	-	5.8		
		V_{IL}	-	-	$V_{CC} \times 0.2$		
	P000 to P004 P010 to P015	V_{IH}	$AV_{CC0} \times 0.8$	-	-		
		V_{IL}	-	-	$AV_{CC0} \times 0.2$		
	EXTAL Input ports pins except for P000 to P004, P010 to P015	V_{IH}	$V_{CC} \times 0.8$	-	-		
		V_{IL}	-	-	$V_{CC} \times 0.2$		

Note 1. P205, P206, P400, P401, P407 (total 5pins)

2.2.3 I/O I_{OH} , I_{OL} **Table 2.6** I/O I_{OH} , I_{OL} Conditions: $V_{CC} = AV_{CC0} = 1.6$ to 5.5 V

Parameter			Symbol	Min	Typ	Max	Unit
Permissible output current (average value per pin)	Ports P000 to P004, P010 to P015, P212, P213	-	I_{OH}	-	-	-4.0	mA
			I_{OL}	-	-	4.0	mA
	Ports P408, P409	Low drive*1	I_{OH}	-	-	-4.0	mA
			I_{OL}	-	-	4.0	mA
		Middle drive*2 $V_{CC} = 2.7$ to 3.0 V	I_{OH}	-	-	-8.0	mA
			I_{OL}	-	-	8.0	mA
		Middle drive*2 $V_{CC} = 3.0$ to 5.5 V	I_{OH}	-	-	-20.0	mA
			I_{OL}	-	-	20.0	mA
	Other output pins*3	Low drive*1	I_{OH}	-	-	-4.0	mA
			I_{OL}	-	-	4.0	mA
		Middle drive*2	I_{OH}	-	-	-8.0	mA
			I_{OL}	-	-	8.0	mA
Permissible output current (max value per pin)	Ports P000 to P004, P010 to P015, P212, P213	-	I_{OH}	-	-	-4.0	mA
			I_{OL}	-	-	4.0	mA
	Ports P408, P409	Low drive*1	I_{OH}	-	-	-4.0	mA
			I_{OL}	-	-	4.0	mA
		Middle drive*2 $V_{CC} = 2.7$ to 3.0 V	I_{OH}	-	-	-8.0	mA
			I_{OL}	-	-	8.0	mA
		Middle drive*2 $V_{CC} = 3.0$ to 5.5 V	I_{OH}	-	-	-20.0	mA
			I_{OL}	-	-	20.0	mA
	Other output pins*3	Low drive*1	I_{OH}	-	-	-4.0	mA
			I_{OL}	-	-	4.0	mA
		Middle drive*2	I_{OH}	-	-	-8.0	mA
			I_{OL}	-	-	8.0	mA
Permissible output current (max value total pins)	Total of ports P000 to P004, P010 to P015		$\Sigma I_{OH} (\text{max})$	-	-	-30	mA
			$\Sigma I_{OL} (\text{max})$	-	-	30	mA
	Total of all output pin		$\Sigma I_{OH} (\text{max})$	-	-	-60	mA
			$\Sigma I_{OL} (\text{max})$	-	-	60	mA

Caution: To protect the reliability of the MCU, the output current values should not exceed the values in this table. The average output current indicates the average value of current measured during 100 μs .

Note 1. This is the value when low driving ability is selected with the Port Drive Capability bit in the PmnPFS register.

Note 2. This is the value when middle driving ability is selected with the Port Drive Capability bit in the register.

Note 3. Except for Ports P200, P214, P215, which are input ports.

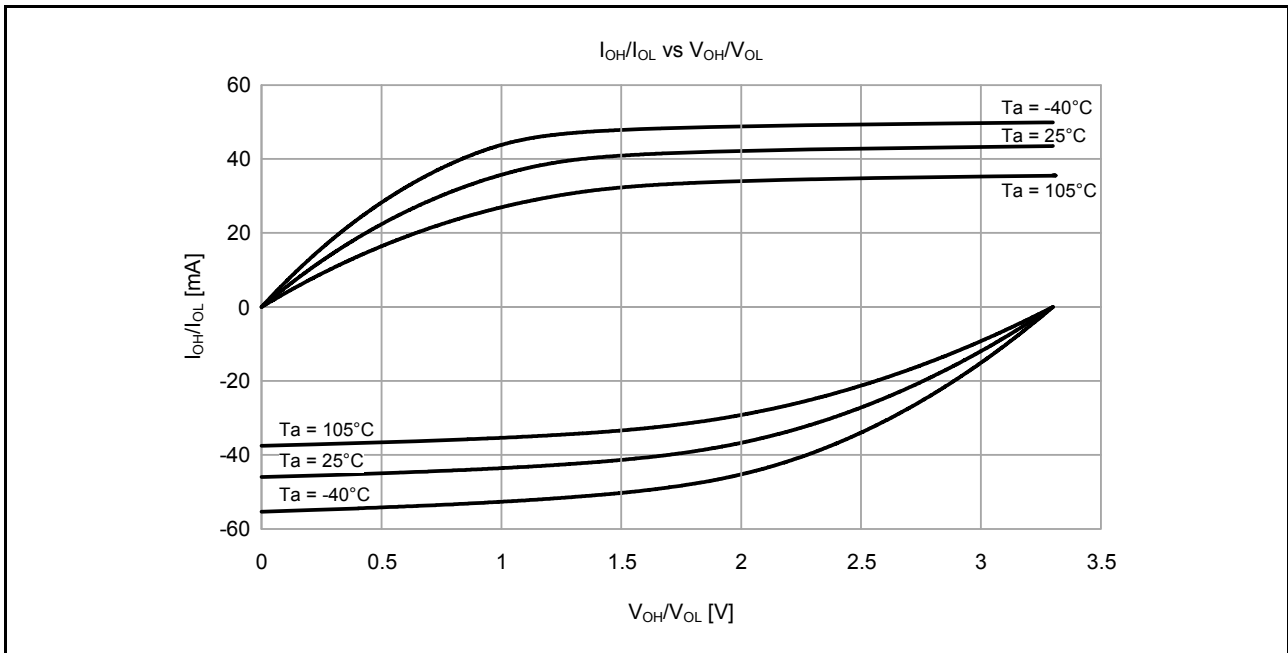


Figure 2.10 V_{OH}/V_{OL} and I_{OH}/I_{OL} temperature characteristics at $V_{CC} = 3.3$ V when middle drive output is selected (reference data)

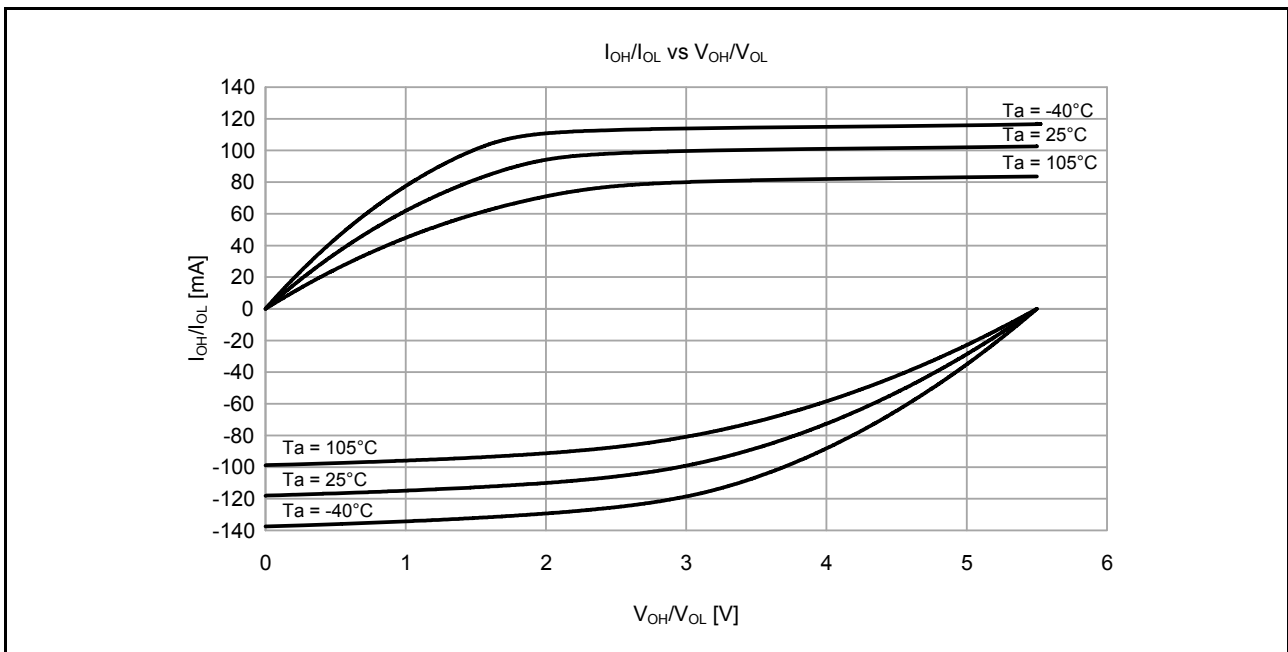


Figure 2.11 V_{OH}/V_{OL} and I_{OH}/I_{OL} temperature characteristics at $V_{CC} = 5.5$ V when middle drive output is selected (reference data)

2.2.7 P408, P409 I/O Pin Output Characteristics of Middle Drive Capacity

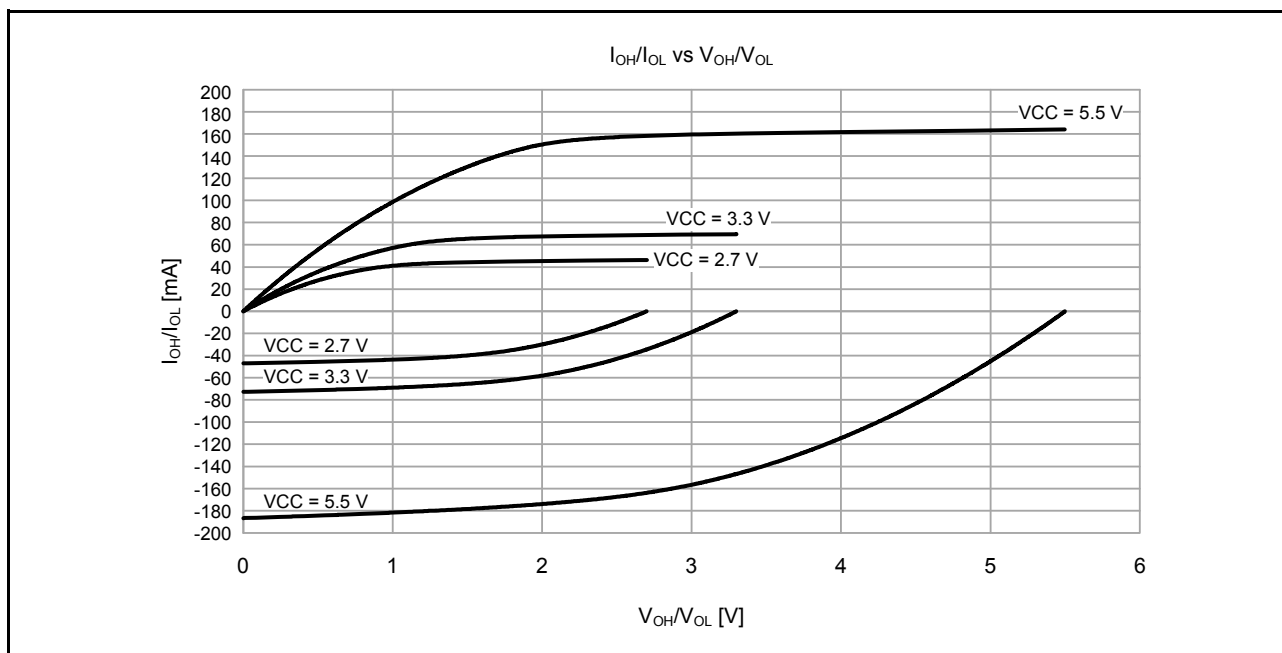


Figure 2.12 V_{OH/V_{OL}} and I_{OH/I_{OL}} voltage characteristics at Ta = 25°C when middle drive output is selected (reference data)

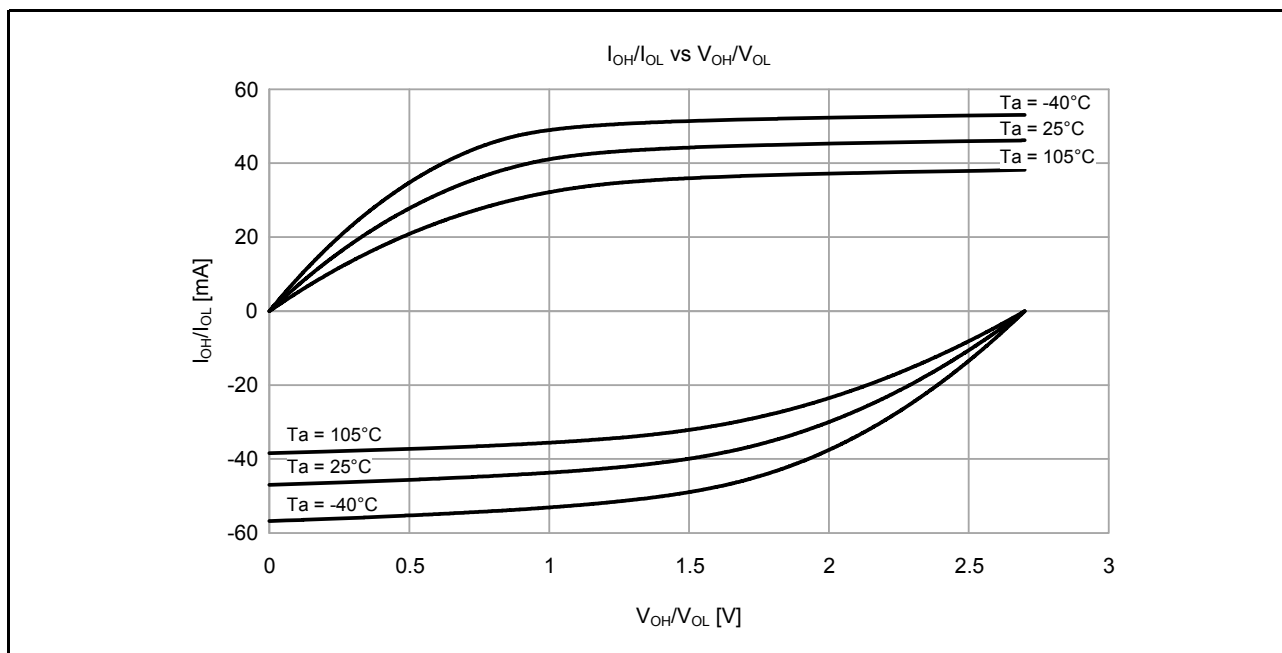


Figure 2.13 V_{OH/V_{OL}} and I_{OH/I_{OL}} temperature characteristics at VCC = 2.7 V when middle drive output is selected (reference data)

2.2.8 IIC I/O Pin Output Characteristics

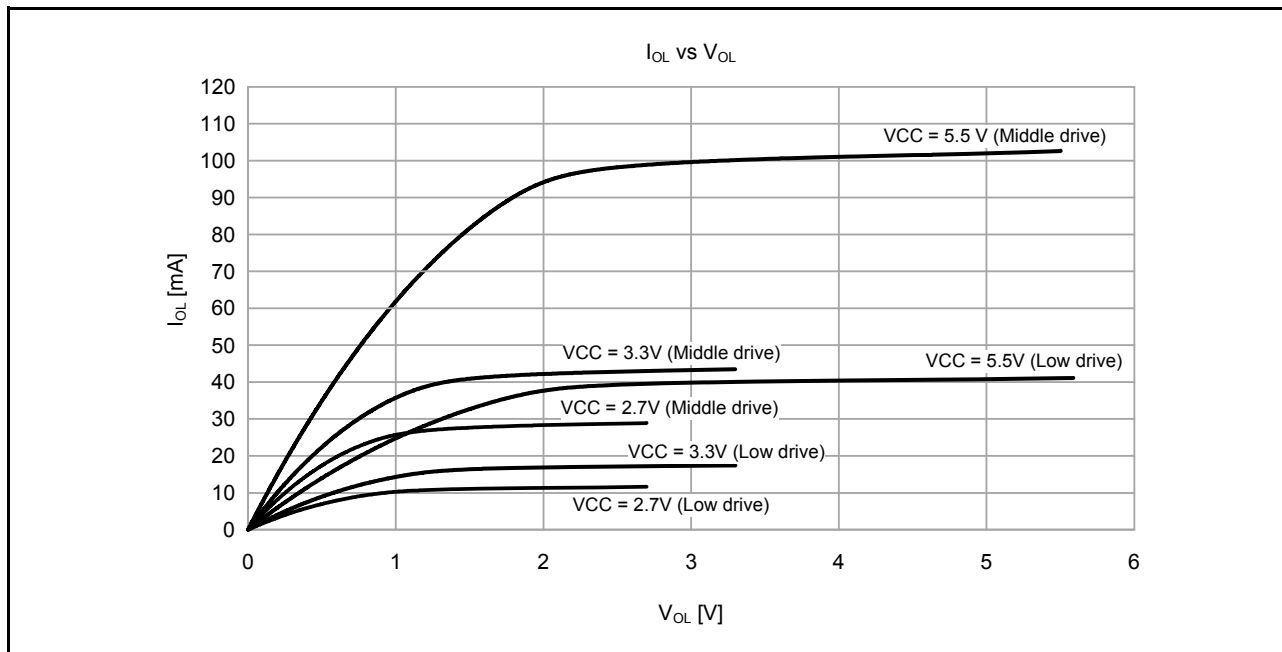


Figure 2.16 V_{OH}/V_{OL} and I_{OH}/I_{OL} voltage characteristics at Ta = 25°C

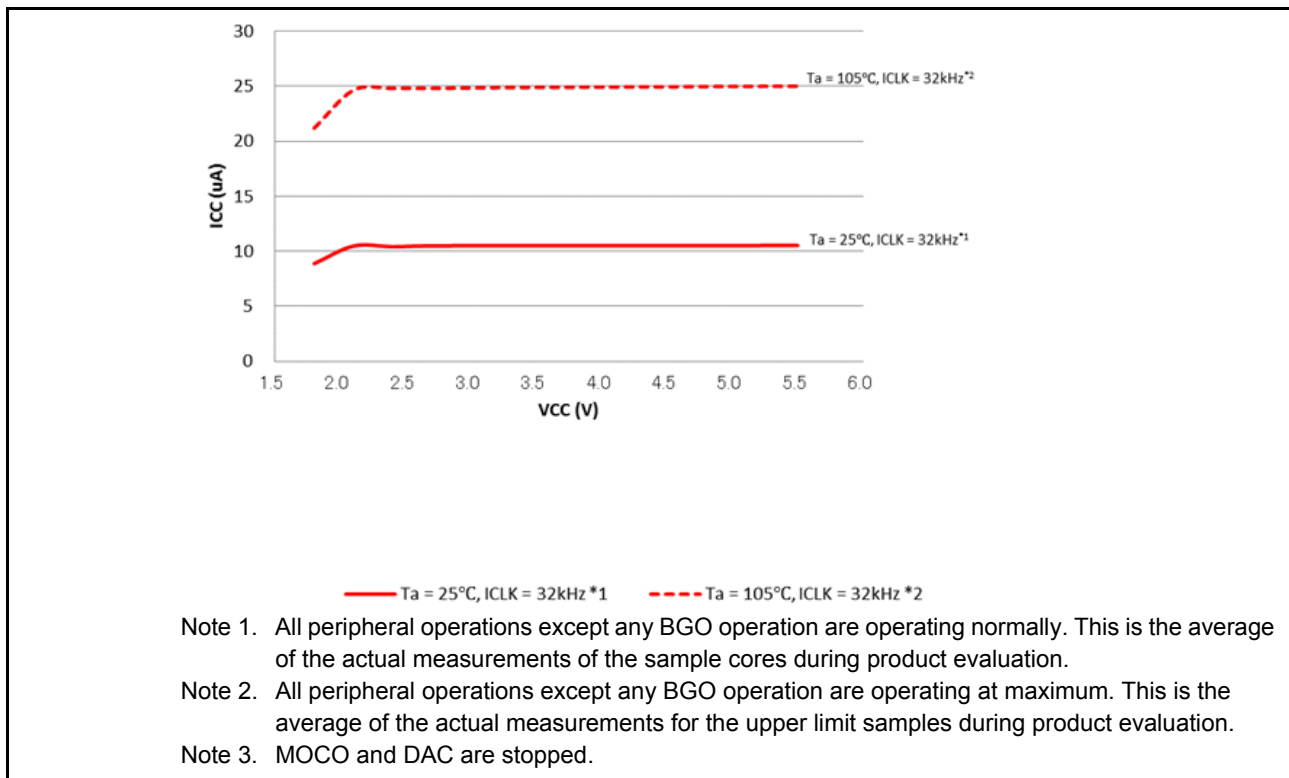


Figure 2.21 Voltage dependency in subosc-speed operating mode (reference data)

Table 2.12 Operating and standby current (2)

Conditions: VCC = AVCC0 = 1.6 to 5.5 V

Parameter		Symbol	Typ*3	Max	Unit	Test conditions	
Supply current*1	Software Standby mode*2	I_{CC}	T _a = 25°C	0.4	1.5	µA	-
			T _a = 55°C	0.6	5.5		
			T _a = 85°C	1.2	10.0		
			T _a = 105°C	2.6	40.0		
	Increment for RTC operation with low-speed on-chip oscillator*4		0.4	-	-		
	Increment for RTC operation with sub-clock oscillator*4		0.5	-	SOMCR.SODRV[1:0] are 11b (Low power mode 3)		
			1.3	-	SOMCR.SODRV[1:0] are 00b (normal mode)		

Note 1. Supply current values do not include output charge/discharge current from all pins. The values apply when internal pull-up MOS transistors are in the off state.

Note 2. The IWDT and LVD are not operating.

Note 3. VCC = 3.3 V.

Note 4. Includes the current of low-speed on-chip oscillator or sub-oscillation circuit.

2.2.10 VCC Rise and Fall Gradient and Ripple Frequency

Table 2.14 Rise and fall gradient characteristics

Conditions: VCC = AVCC0 = 0 to 5.5 V

Parameter		Symbol	Min	Typ	Max	Unit	Test conditions
Power-on VCC rising gradient	Voltage monitor 0 reset disabled at startup	SrVCC	0.02	-	2	ms/V	-
	Voltage monitor 0 reset enabled at startup*1, *2		0.02	-	-		
	SCI Boot mode*2		0.02	-	2		

Note 1. When OFS1.LVDAS = 0.

Note 2. At boot mode, the reset from voltage monitor 0 is disabled regardless of the value of OFS1.LVDAS bit.

Table 2.15 Rising and falling gradient and ripple frequency characteristics

Conditions: VCC = AVCC0 = 1.6 to 5.5 V

The ripple voltage must meet the allowable ripple frequency $f_{r(VCC)}$ within the range between the VCC upper limit (5.5 V) and lower limit (1.6 V).

When the VCC change exceeds VCC $\pm 10\%$, the allowable voltage change rising and falling gradient $dt/dVCC$ must be met.

Parameter	Symbol	Min	Typ	Max	Unit	Test conditions
Allowable ripple frequency	$f_{r(VCC)}$	-	-	10	kHz	Figure 2.24 $V_{r(VCC)} \leq VCC \times 0.2$
		-	-	1	MHz	Figure 2.24 $V_{r(VCC)} \leq VCC \times 0.08$
		-	-	10	MHz	Figure 2.24 $V_{r(VCC)} \leq VCC \times 0.06$
Allowable voltage change rising and falling gradient	$dt/dVCC$	1.0	-	-	ms/V	When VCC change exceeds VCC $\pm 10\%$

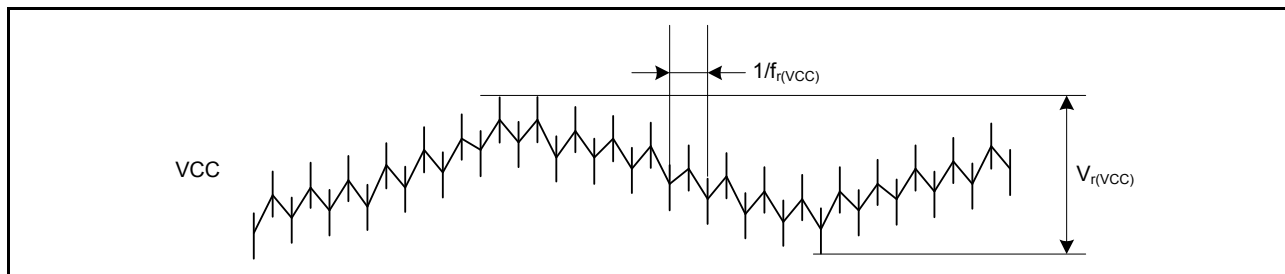


Figure 2.24 Ripple waveform

2.3.2 Clock Timing

Table 2.21 Clock timing (1 of 2)

Parameter	Symbol	Min	Typ	Max	Unit	Test conditions		
EXTAL external clock input cycle time	t_{Xcyc}	50	-	-	ns	Figure 2.25		
EXTAL external clock input high pulse width	t_{XH}	20	-	-	ns			
EXTAL external clock input low pulse width	t_{XL}	20	-	-	ns			
EXTAL external clock rising time	t_{Xr}	-	-	5	ns			
EXTAL external clock falling time	t_{Xf}	-	-	5	ns			
EXTAL external clock input wait time*1	t_{EXWT}	0.3	-	-	μ s	-		
EXTAL external clock input frequency	f_{EXTAL}	-	-	20	MHz	$2.4 \leq VCC \leq 5.5$		
		-	-	8		$1.8 \leq VCC < 2.4$		
		-	-	1		$1.6 \leq VCC < 1.8$		
Main clock oscillator oscillation frequency	f_{MAIN}	1	-	20	MHz	$2.4 \leq VCC \leq 5.5$		
		1	-	8		$1.8 \leq VCC < 2.4$		
		1	-	4		$1.6 \leq VCC < 1.8$		
LOCO clock oscillation frequency	f_{LOCO}	27.8528	32.768	37.6832	kHz	-		
LOCO clock oscillation stabilization time	t_{LOCO}	-	-	100	μ s	Figure 2.26		
IWDT-dedicated clock oscillation frequency	f_{ILOCO}	12.75	15	17.25	kHz	-		
MOCO clock oscillation frequency	f_{MOCO}	6.8	8	9.2	MHz	-		
MOCO clock oscillation stabilization time	t_{MOCO}	-	-	1	μ s	-		
HOCO clock oscillation frequency	f_{HOCO24}	23.64	24	24.36	MHz	$T_a = -40$ to -20°C $1.8 \leq VCC \leq 5.5$		
		22.68	24	25.32		$T_a = -40$ to 85°C $1.6 \leq VCC < 1.8$		
		23.76	24	24.24		$T_a = -20$ to 85°C $1.8 \leq VCC \leq 5.5$		
		23.52	24	24.48		$T_a = 85$ to 105°C $2.4 \leq VCC \leq 5.5$		
	f_{HOCO32}	31.52	32	32.48		$T_a = -40$ to -20°C $1.8 \leq VCC \leq 5.5$		
		30.24	32	33.76		$T_a = -40$ to 85°C $1.6 \leq VCC < 1.8$		
		31.68	32	32.32		$T_a = -20$ to 85°C $1.8 \leq VCC \leq 5.5$		
		31.36	32	32.64		$T_a = 85$ to 105°C $2.4 \leq VCC \leq 5.5$		
	f_{HOCO48}^{*3}	47.28	48	48.72		$T_a = -40$ to -20°C $1.8 \leq VCC \leq 5.5$		
		47.52	48	48.48		$T_a = -20$ to 85°C $1.8 \leq VCC \leq 5.5$		
		47.04	48	48.96		$T_a = 85$ to 105°C $2.4 \leq VCC \leq 5.5$		
	f_{HOCO64}^{*4}	63.04	64	64.96		$T_a = -40$ to -20°C $2.4 \leq VCC \leq 5.5$		
		63.36	64	64.64		$T_a = -20$ to 85°C $2.4 \leq VCC \leq 5.5$		
		62.72	64	65.28		$T_a = 85$ to 105°C $2.4 \leq VCC \leq 5.5$		
	HOCO clock oscillation stabilization time*5, *6	Except low-voltage mode	t_{HOCO24}	-		-	μ s	Figure 2.27
			t_{HOCO32}	-		-		
t_{HOCO48}			-	-				
t_{HOCO64}		-	-					
Low-voltage mode		t_{HOCO24}	-	-	37.1			
		t_{HOCO32}	-	-	43.3			
		t_{HOCO48}	-	-	80.6			
	t_{HOCO64}	-	-	100.9				
Sub-clock oscillator oscillation frequency	f_{SUB}	-	32.768	-	kHz	-		

2.3.4 Wakeup Time

Table 2.23 Timing of recovery from low power modes (1)

Parameter				Symbol	Min	Typ	Max	Unit	Test conditions
Recovery time from Software Standby mode*1	High-speed mode	Crystal resonator connected to main clock oscillator	System clock source is main clock oscillator (20 MHz)*2	t _{SBYMC}	-	2	3	ms	Figure 2.31
		External clock input to main clock oscillator	System clock source is main clock oscillator (20 MHz)*3	t _{SBYEX}	-	14	25	μs	
		System clock source is HOCO*4 (HOCO clock is 32 MHz)		t _{SBYHO}	-	43	52	μs	
		System clock source is HOCO*4 (HOCO clock is 48 MHz)		t _{SBYHO}	-	44	52	μs	
		System clock source is HOCO*5 (HOCO clock is 64 MHz)		t _{SBYHO}	-	82	110	μs	
		System clock source is MOCO		t _{SBYMO}	-	16	25	μs	

Note 1. The division ratio of ICK and PCKx is the minimum division ratio within the allowable frequency range. The recovery time is determined by the system clock source.

Note 2. The Main Clock Oscillator Wait Control Register (MOSCWTCR) is set to 05h.

Note 3. The Main Clock Oscillator Wait Control Register (MOSCWTCR) is set to 00h.

Note 4. The HOCO clock wait control register (HOCOWTCR) is set to 05h.

Note 5. The HOCO clock wait control register (HOCOWTCR) is set to 06h.

Table 2.24 Timing of recovery from low power modes (2)

Parameter				Symbol	Min	Typ	Max	Unit	Test conditions
Recovery time from Software Standby mode*1	Middle-speed mode	Crystal resonator connected to main clock oscillator	System clock source is main clock oscillator (12 MHz)*2	t _{SBYMC}	-	2	3	ms	Figure 2.31
		External clock input to main clock oscillator	System clock source is main clock oscillator (12 MHz)*3	t _{SBYEX}	-	2.9	10	μs	
		System clock source is HOCO*4		t _{SBYHO}	-	38	50	μs	
		System clock source is MOCO		t _{SBYMO}	-	3.5	5.5	μs	

Note 1. The division ratio of ICK and PCKx is the minimum division ratio within the allowable frequency range. The recovery time is determined by the system clock source.

Note 2. The Main Clock Oscillator Wait Control Register (MOSCWTCR) is set to 05h.

Note 3. The Main Clock Oscillator Wait Control Register (MOSCWTCR) is set to 00h.

Note 4. The system clock is 12 MHz.

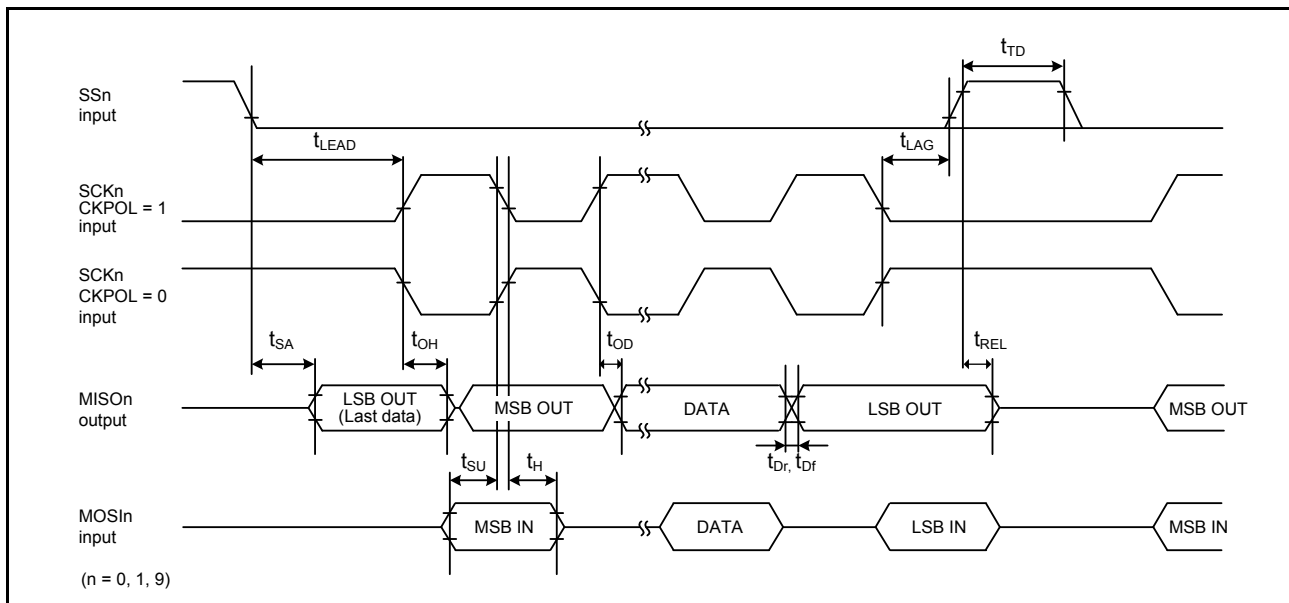


Figure 2.47 SCI simple SPI mode timing (slave, CKPH = 0)

Table 2.34 SCI timing (3)

Conditions: VCC = AVCC0 = 2.7 to 5.5 V

Parameter	Symbol	Min	Max	Unit	Test conditions	
Simple IIC (Standard mode)	SDA input rise time	t_{Sr}	-	1000	ns	Figure 2.48
	SDA input fall time	t_{Sf}	-	300	ns	
	SDA input spike pulse removal time	t_{SP}	0	$4 \times t_{IICcyc}$	ns	
	Data input setup time	t_{SDAS}	250	-	ns	
	Data input hold time	t_{SDAH}	0	-	ns	
	SCL, SDA capacitive load	C_b^{*1}	-	400	pF	
Simple IIC*2 (Fast mode)	SDA input rise time	t_{Sr}	-	300	ns	Figure 2.48
	SDA input fall time	t_{Sf}	-	300	ns	
	SDA input spike pulse removal time	t_{SP}	0	$4 \times t_{IICcyc}$	ns	
	Data input setup time	t_{SDAS}	100	-	ns	
	Data input hold time	t_{SDAH}	0	-	ns	
	SCL, SDA capacitive load	C_b^{*1}	-	400	pF	

Note: t_{IICcyc} : Clock cycle selected by the SMR.CKS[1:0] bits.

Note 1. C_b indicates the total capacity of the bus line.

Note 2. Middle drive output is selected in the Port Drive Capability bit in the PmnPFS register.

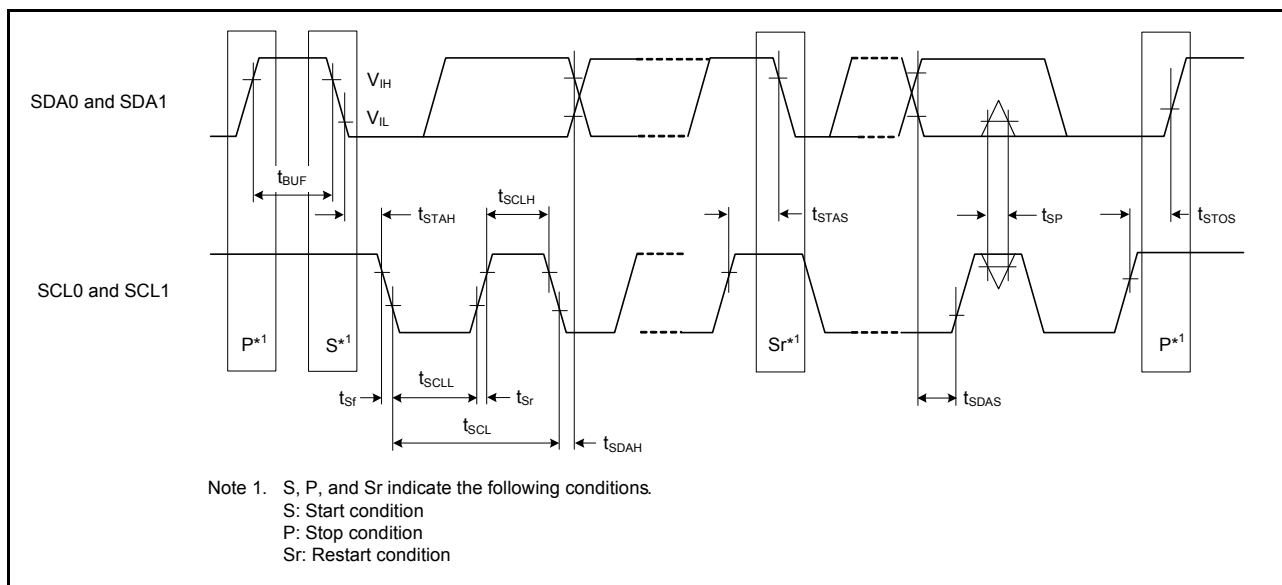


Figure 2.56 I²C bus interface input/output timing

2.3.11 CLKOUT Timing

Table 2.37 CLKOUT timing

Parameter		Symbol	Min	Max	Unit*1	Test conditions	
CLKOUT	CLKOUT pin output cycle*1	VCC = 2.7 V or above	t _{Cyc}	62.5	-	ns	Figure 2.57
		VCC = 1.8 V or above		125	-		
		VCC = 1.6 V or above		250	-		
	CLKOUT pin high pulse width*2	VCC = 2.7 V or above	t _{CH}	15	-	ns	
		VCC = 1.8 V or above		30	-		
		VCC = 1.6 V or above		150	-		
	CLKOUT pin low pulse width*2	VCC = 2.7 V or above	t _{CL}	15	-	ns	
		VCC = 1.8 V or above		30	-		
		VCC = 1.6 V or above		150	-		
	CLKOUT pin output rise time	VCC = 2.7 V or above	t _{Cr}	-	12	ns	
		VCC = 1.8 V or above		-	25		
		VCC = 1.6 V or above		-	50		
CLKOUT pin output fall time	VCC = 2.7 V or above	t _{Cf}	-	12	ns		
	VCC = 1.8 V or above		-	25			
	VCC = 1.6 V or above		-	50			

Note 1. When the EXTAL external clock input or an oscillator is used with division by 1 (the CKOCR.CKOSSEL[2:0] bits are 011b and the CKOCR.CKODIV[2:0] bits are 000b) to output from CLKOUT, the above should be satisfied with an input duty cycle of 45 to 55%.

Note 2. When the MOCO is selected as the clock output source (the CKOCR.CKOSSEL[2:0] bits are 001b), set the clock output division ratio selection to be divided by 2 (the CKOCR.CKODIV[2:0] bits are 001b).

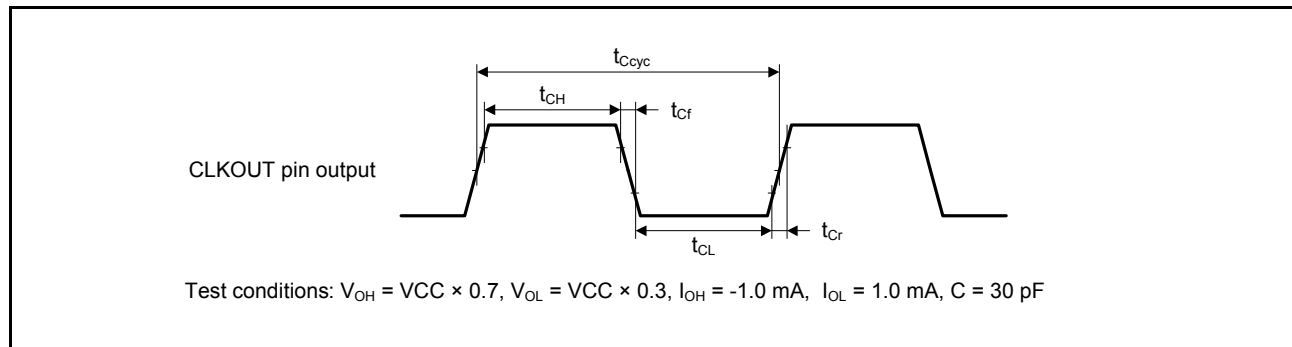


Figure 2.57 CLKOUT output timing

Table 2.42 A/D conversion characteristics (3) in high-speed A/D conversion mode (2 of 2)

Conditions: VCC = AVCC0 = 2.4 to 5.5 V, VREFH0 = 2.4 to 5.5 V, VSS = AVSS0 = VREFL0 = 0V
Reference voltage range applied to the VREFH0 and VREFL0.

Parameter		Min	Typ	Max	Unit	Test Conditions
DNL differential nonlinearity error		-	±1.0	-	LSB	-
INL integral nonlinearity error		-	±1.0	±3.0	LSB	-
14-bit mode						
Resolution		-	-	14	Bit	-
Conversion time*1 (Operation at PCLKD = 32 MHz)	Permissible signal source impedance Max. = 1.3 kΩ	1.59	-	-	μs	High-precision channel ADCSR.ADHSC = 0 ADSSSTRn.SST[7:0] = 0Dh
		2.44	-	-	μs	Normal-precision channel ADCSR.ADHSC = 0 ADSSSTRn.SST[7:0] = 28h
Offset error		-	±2.0	±18	LSB	High-precision channel
				±24.0	LSB	Other than above
Full-scale error		-	±3.0	±18	LSB	High-precision channel
				±24.0	LSB	Other than above
Quantization error		-	±0.5	-	LSB	-
Absolute accuracy		-	±5.0	±20	LSB	High-precision channel
				±32.0	LSB	Other than above
DNL differential nonlinearity error		-	±4.0	-	LSB	-
INL integral nonlinearity error		-	±4.0	±12.0	LSB	-

Note: The characteristics apply when no pin functions other than 14-bit A/D converter input are used. Absolute accuracy does not include quantization errors. Offset error, full-scale error, DNL differential nonlinearity error, and INL integral nonlinearity error do not include quantization errors.

Note 1. The conversion time is the sum of the sampling time and the comparison time. The number of sampling states is indicated for the test conditions.

Note 2. Except for I/O input capacitance (C_{in}), see [section 2.2.4, I/O VOH, VOL, and Other Characteristics](#).

Note 3. Reference data.

Table 2.43 A/D conversion characteristics (4) in low-power A/D conversion mode (1 of 2)

Conditions: VCC = AVCC0 = 2.7 to 5.5 V, VREFH0 = 2.7 to 5.5 V, VSS = AVSS0 = VREFL0 = 0V
Reference voltage range applied to the VREFH0 and VREFL0.

Parameter		Min	Typ	Max	Unit	Test Conditions
Frequency		1	-	24	MHz	-
Analog input capacitance*2	Cs	-	-	8*3	pF	High-precision channel
		-	-	9*3	pF	Normal-precision channel
Analog input resistance	Rs	-	-	2.5*3	kΩ	High-precision channel
		-	-	6.7*3	kΩ	Normal-precision channel
Analog input voltage range	A _{in}	0	-	VREFH0	V	-
12-bit mode						
Resolution		-	-	12	Bit	-
Conversion time*1 (Operation at PCLKD = 24 MHz)	Permissible signal source impedance Max. = 1.1 kΩ	2.25	-	-	μs	High-precision channel ADCSR.ADHSC = 1 ADSSSTRn.SST[7:0] = 0Dh
		3.38	-	-	μs	Normal-precision channel ADCSR.ADHSC = 1 ADSSSTRn.SST[7:0] = 28h
Offset error		-	±0.5	±4.5	LSB	High-precision channel
				±6.0	LSB	Other than above
Full-scale error		-	±0.75	±4.5	LSB	High-precision channel
				±6.0	LSB	Other than above
Quantization error		-	±0.5	-	LSB	-

2.11 Comparator Characteristics

Table 2.55 ACMPLP characteristics

Conditions: VCC = AVCC0 = 1.8 to 5.5 V, VSS = AVSS0 = 0 V

Parameter	Symbol	Min	Typ	Max	Unit	Test conditions	
Reference voltage range	V_{REF}	0	-	VCC -1.4	V	-	
Input voltage range	V_I	0	-	VCC	V	-	
Internal reference voltage	-	1.36	1.44	1.50	V	-	
Output delay	High-speed mode	T_d	-	-	1.2	μ s	VCC = 3.0 Slew rate of input signal > 50 mV/ μ s
	Low-speed mode		-	-	5	μ s	
	Window mode		-	-	2	μ s	
Offset voltage	High-speed mode	-	-	-	50	mV	-
	Low-speed mode	-	-	-	40	mV	-
	Window mode	-	-	-	60	mV	-
Internal reference voltage for window mode	V_{RFH}	-	$0.76 \times$ VCC	-	V	-	
	V_{RFL}	-	$0.24 \times$ VCC	-	V	-	
Operation stabilization wait time	T_{cmp}	100	-	-	μ s	-	

Table 2.58 Code flash characteristics (3)

Middle-speed operating mode

Conditions: VCC = AVCC0 = 1.8 to 5.5 V, Ta = -40 to +85°C

Parameter		Symbol	ICLK = 1 MHz			ICLK = 8 MHz			Unit
			Min	Typ	Max	Min	Typ	Max	
Programming time	4-byte	t _{P4}	-	157	1411	-	101	966	μs
Erase time	1-KB	t _{E1K}	-	9.10	289	-	6.10	228	ms
Blank check time	2-byte	t _{BC4}	-	-	87.7	-	-	52.5	μs
	1-KB	t _{BC1K}	-	-	1930	-	-	414	μs
Erase suspended time		t _{SED}	-	-	32.7	-	-	21.6	μs
Startup area switching setting time		t _{SAS}	-	22.8	592	-	14.2	465	ms
Access window time		t _{AWS}	-	22.8	592	-	14.2	465	ms
OCD/serial programmer ID setting time		t _{OSIS}	-	22.8	592	-	14.2	465	ms
Flash memory mode transition wait time 1		t _{DIS}	2	-	-	2	-	-	μs
Flash memory mode transition wait time 2		t _{MS}	720	-	-	720	-	-	ns

Note 1. Does not include the time until each operation of the flash memory is started after instructions are executed by the software.

Note 2. The lower-limit frequency of ICLK is 1 MHz during programming or erasing the flash memory. When using ICLK at below 4 MHz, the frequency can be set to 1 MHz, 2 MHz, or 3 MHz. A non-integer frequency such as 1.5 MHz cannot be set.

Note 3. The frequency accuracy of ICLK must be ±3.5% while programming or erasing the flash memory. Confirm the frequency accuracy of the clock source.

2.12.2 Data Flash Memory Characteristics

Table 2.59 Data flash characteristics (1)

Parameter		Symbol	Min	Typ	Max	Unit	Conditions
Reprogramming/erase cycle*1		N _{DPEC}	100000	1000000	-	Times	-
Data hold time	After 10000 times of N _{DPEC}	t _{DDRP}	20*2, *3	-	-	Year	Ta = +85°C
	After 100000 times of N _{DPEC}		5*2, *3	-	-	Year	
	After 1000000 times of N _{DPEC}		-	1*2, *3	-	Year	

Note 1. The reprogram/erase cycle is the number of erasure for each block. When the reprogram/erase cycle is n times (n = 100,000), erasing can be performed n times for each block. For instance, when 1-byte programming is performed 1,000 times for different addresses in 1-byte blocks, and then the entire block is erased, the reprogram/erase cycle is counted as 1. However, programming the same address for several times as one erasure is not enabled. (overwriting is prohibited.)

Note 2. Characteristics when using the flash memory programmer and the self-programming library provided by Renesas Electronics.

Note 3. These results are obtained from reliability testing.

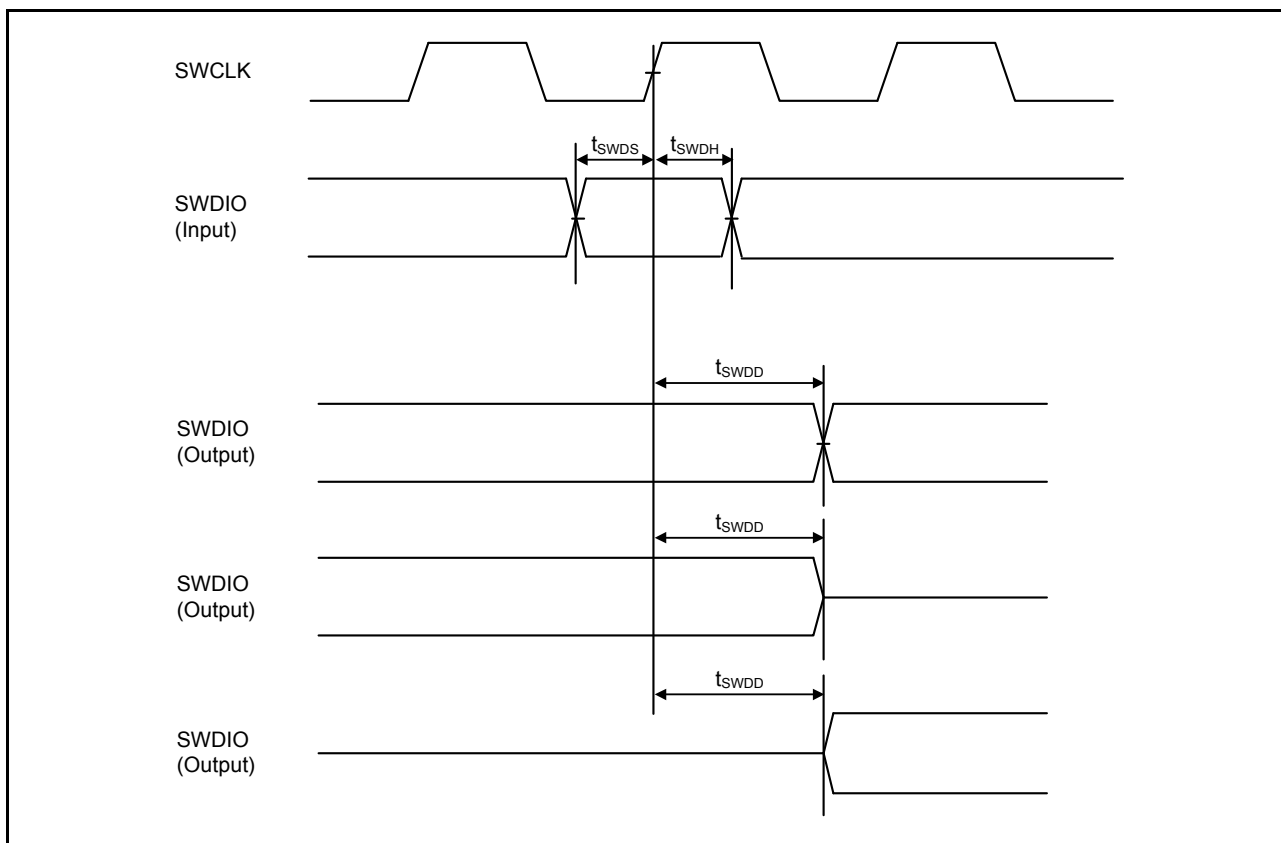
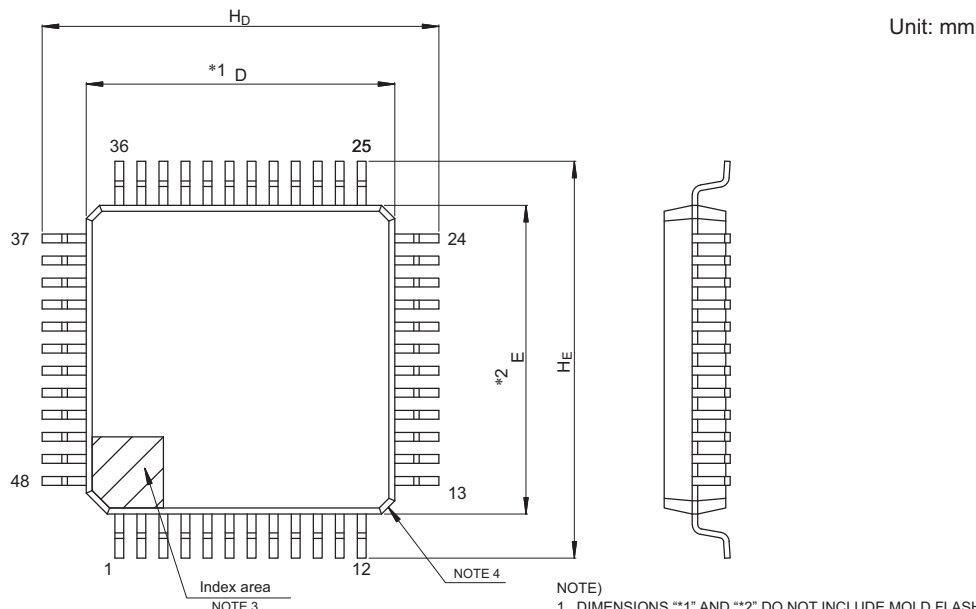
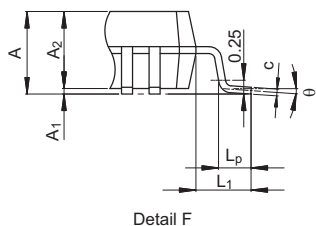
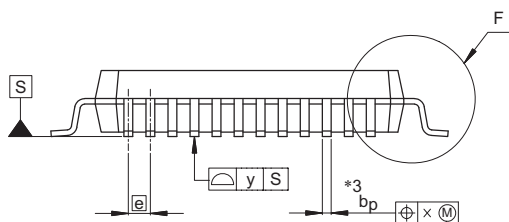


Figure 2.72 SWD input output timing

JEITA Package Code	RENESAS Code	Previous Code	MASS (Typ) [g]
P-LFQFP48-7x7-0.50	PLQP0048KB-B	—	0.2



- NOTE)
1. DIMENSIONS **1" AND **2" DO NOT INCLUDE MOLD FLASH.
 2. DIMENSION **3" DOES NOT INCLUDE TRIM OFFSET.
 3. PIN 1 VISUAL INDEX FEATURE MAY VARY, BUT MUST BE LOCATED WITHIN THE HATCHED AREA.
 4. CHAMFERS AT CORNERS ARE OPTIONAL, SIZE MAY VARY.



Reference Symbol	Dimensions in millimeters		
	Min	Nom	Max
D	6.9	7.0	7.1
E	6.9	7.0	7.1
A ₂	—	1.4	—
H _D	8.8	9.0	9.2
H _E	8.8	9.0	9.2
A	—	—	1.7
A ₁	0.05	—	0.15
b _p	0.17	0.20	0.27
c	0.09	—	0.20
θ	0°	3.5°	8°
e	—	0.5	—
x	—	—	0.08
y	—	—	0.08
L _p	0.45	0.6	0.75
L ₁	—	1.0	—

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Figure 1.2 LQFP 48-pin